Session Program

25–28 Jun 2006

8th RD50 Workshop

Defect Engineering

Prague

Tuesday 27 June

09:00

Defect Engineering

Session | **Location:** Prague

09:00–09:20 **Status report on new epi-devices**

Speaker
Eckhart Fretwurst

09:20–09:40 **Measurement of Trapping Time Constants in Neutron Irradiated Pad Detectors**

Speaker
Jens Weber

09:40–10:00 **Annealing studies of effective trapping times in silicon detectors**

Speaker
Matej Batic

10:00–10:20 **Recent CCE measurements with neutron irradiated epi-Si pad detectors**

Speaker
Gregor Kramberger

10:20–10:50 **Coffee break**

10:50